

### N-Channel 500V (D-S)Power MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	500				
$R_{DS(on)}(\Omega)$	V <sub>GS</sub> = 10 V 0.660				
Q <sub>g</sub> (Max.) (nC)	81				
Q <sub>gs</sub> (nC)	20				
Q <sub>gd</sub> (nC)	36				
Configuration	Single				

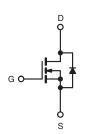
#### **FEATURES**

• Lower Gate Charge Qq Results in Simpler Drive



- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage
- Compliant to RoHS Directive 2002/95/EC





N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V <sub>DS</sub>	500	V	
Gate-Source Voltage			V <sub>GS</sub>	± 20	V	
Continuous Drain Current	V -+ 10 V	T <sub>C</sub> = 25 °C	I <sub>D</sub>	13		
Continuous Drain Current	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 100 °C		8.1	Α	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	50		
Linear Derating Factor				2.0	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	560	mJ	
Avalanche Current <sup>a</sup>			I <sub>AR</sub>	13	А	
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	25	mJ	
Maximum Power Dissipation $T_C = 25  ^{\circ}C$			P <sub>D</sub>	250	W	
Peak Diode Recovery dV/dt <sup>c</sup>			dV/dt	9.2	V/ns	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature) for 10 s				300 <sup>d</sup>		
Maurina Taraus	6-32 or M3 screw			10	lbf · in	
Mounting Torque				1.1	N · m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Starting T<sub>J</sub> = 25 °C, L = 5.7 mH, R<sub>g</sub> = 25  $\Omega$ , I<sub>AS</sub> =14 A, dV/dt = 7.6 V/ns (see fig. 12a). c. I<sub>SD</sub>  $\leq$  14 A, dI/dt  $\leq$  250 A/µs, V<sub>DD</sub>  $\leq$  V<sub>DS</sub>, T<sub>J</sub>  $\leq$  150 °C.

- d. 1.6 mm from case.



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	62			
Case-to-Sink, Flat, Greasd Surface	R <sub>thCS</sub>	0.50	-	°C/W		
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	0.50			

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	ce to 25 °C, I <sub>D</sub> = 1 mA	-	0.55	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> :	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		-	4.0	V
Gate-Source Leakage	I <sub>GSS</sub>		V <sub>GS</sub> = ± 20V	-	-	±100	nA
Zono Coto Voltano Dusin Comunit		V <sub>DS</sub> = 500 V, V <sub>GS</sub> = 0 V		-	-	25	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 400 \	/, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	250	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 8.4 A <sup>b</sup>	-	0.660	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub>	= 50 V, I <sub>D</sub> = 8.4 A	8.1	-	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>		$V_{GS} = 0 V$ ,		1910	-	
Output Capacitance	C <sub>oss</sub>	1	$V_{DS} = 25 V$ ,	-	290	-	1
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.0 MHz, see fig. 5		-	11	-	_
Output Capacitance	C <sub>oss</sub>	V <sub>GS</sub> = 0 V	V <sub>DS</sub> = 1.0 V, f = 1.0 MHz	-	2730	-	- pF -
			V <sub>DS</sub> = 400 V, f = 1.0 MHz	-	82	-	
Effective Output Capacitance	C <sub>oss</sub> eff.	1	V <sub>DS</sub> = 0 V to 400 V <sup>c</sup>	-	160	-	
Total Gate Charge	Qg			-	-	81	
Gate-Source Charge	$Q_{gs}$		I <sub>D</sub> = 14 A, V <sub>DS</sub> = 400 V, see fig. 6 and 13 <sup>b</sup>		-	20	nC ns
Gate-Drain Charge	$Q_{gd}$				-	36	
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>GS</sub> = 10 V		-	15	-	
Rise Time	t <sub>r</sub>		$V_{DD} = 250 \text{ V, } I_{D} = 14 \text{ A,} \ R_{g} = 7.5 \Omega, \ \text{see fig. } 10^{\text{b}}$		39	-	
Turn-Off Delay Time	t <sub>d(off)</sub>				39	-	
Fall Time	t <sub>f</sub>			-	31	-	
Drain-Source Body Diode Characteristic	es						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	13	Α
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	56	
Body Diode Voltage	$V_{SD}$	$T_J = 25 ^{\circ}\text{C},  I_S = 14  \text{A},  V_{GS} = 0  \text{V}^{\text{b}}$		-	-	1.5	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = 14 A, T <sub>J</sub> = 125 °C, dl/dt = 100 A/μs <sup>b</sup>		-	370	550	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	4.4	6.5	μC
Body Diode Reverse Recovery Current	I <sub>RRM</sub>			-	21	31	Α
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> and L <sub>D</sub>				L <sub>D</sub> )	

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width  $\leq$  300  $\mu$ s; duty cycle  $\leq$  2 %. c.  $C_{oss}$  eff. is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DS}$ .



### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

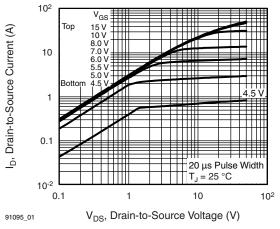


Fig. 1 - Typical Output Characteristics

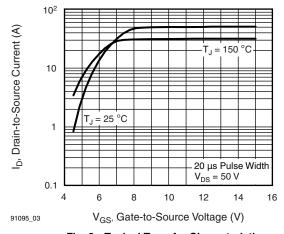


Fig. 3 - Typical Transfer Characteristics

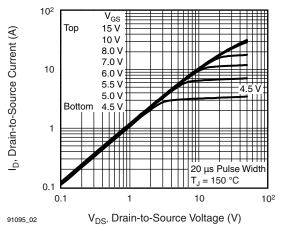


Fig. 2 - Typical Output Characteristics

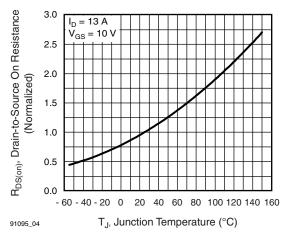


Fig. 4 - Normalized On-Resistance vs. Temperature



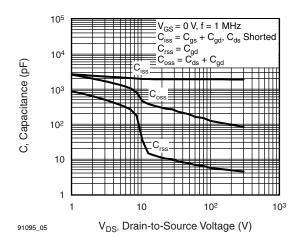


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

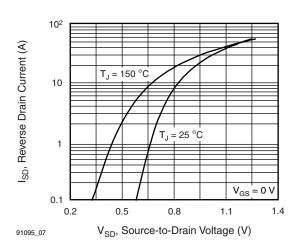


Fig. 7 - Typical Source-Drain Diode Forward Voltage

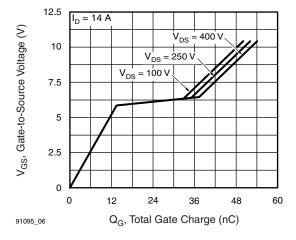


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

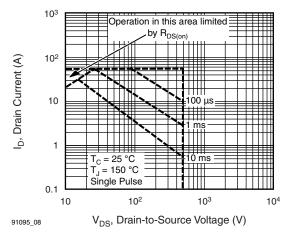


Fig. 8 - Maximum Safe Operating Area



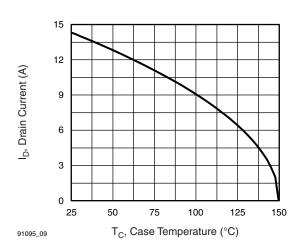


Fig. 9 - Maximum Drain Current vs. Case Temperature

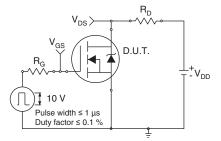


Fig. 10a - Switching Time Test Circuit

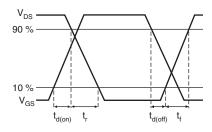


Fig. 10b - Switching Time Waveforms

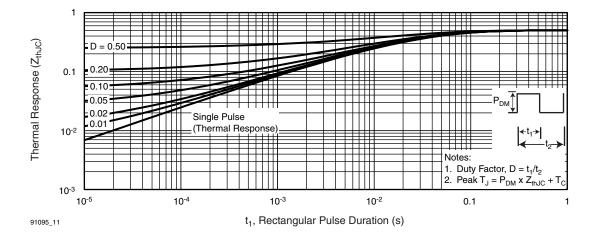
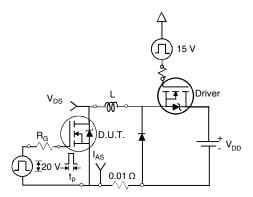
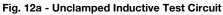


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case







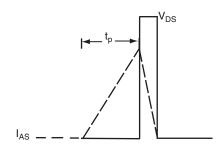


Fig. 12b - Unclamped Inductive Waveforms

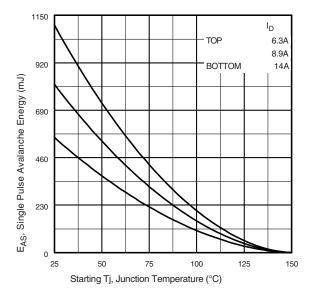


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

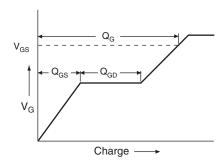


Fig. 13a - Basic Gate Charge Waveform

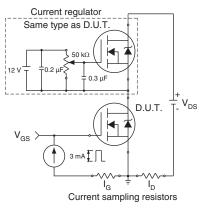
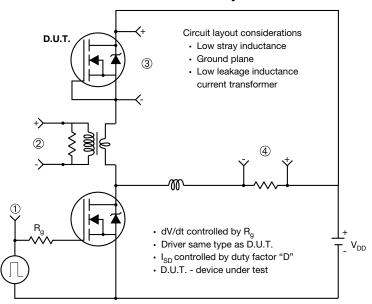


Fig. 13b - Gate Charge Test Circuit



### Peak Diode Recovery dV/dt Test Circuit



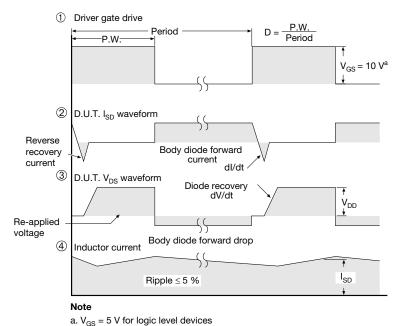
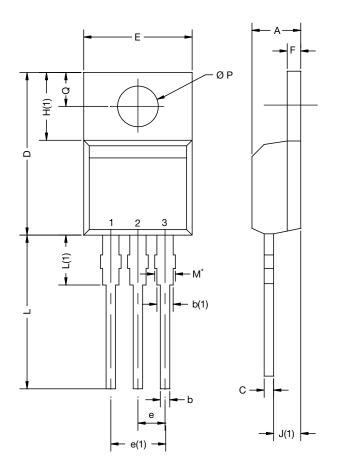


Fig. 14 - For N-Channel



### TO-220-1



DIM.	MILLIM	IETERS	INCHES			
DIM.	MIN.	MAX.	MIN.	MAX.		
Α	4.24	4.65	0.167	0.183		
b	0.69	1.02	0.027	0.040		
b(1)	1.14	1.78	0.045	0.070		
С	0.36	0.61	0.014	0.024		
D	14.33	15.85	0.564	0.624		
Е	9.96	10.52	0.392	0.414		
е	2.41	2.67	0.095	0.105		
e(1)	4.88	5.28	0.192	0.208		
F	1.14	1.40	0.045	0.055		
H(1)	6.10	6.71	0.240	0.264		
J(1)	2.41	2.92	0.095	0.115		
L	13.36	14.40	0.526	0.567		
L(1)	3.33	4.04	0.131	0.159		
ØР	3.53	3.94	0.139	0.155		
Q	2.54	3.00	0.100	0.118		
ECN: X15-0364-Rev. C, 14-Dec-15 DWG: 6031						

#### Note

 $\bullet$   $M^{\star}=0.052$  inches to 0.064 inches (dimension including protrusion), heatsink hole for HVM



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